



55492
2013/
IEC/PAS 62137-3:2008

3

IEC/PAS 62137-3:2008

**Electronics assembly technology — Part 3: Selection guidance of environmental
and endurance test methods for solder joints
(IDT)**



2014

55492—201 /PAS 62137-3:2008

1 « - ») « » « - » (1
« / 91 , , 4
2 , , 420 « 3 «
» ,
3 28 2013 . 37 S-
4 IEC/PAS 62137-3:2008 « -
. 3.
» (IEC/PAS 62137- 3:2008 «Electronics assembly technology — Part 3:
Selection guidance of environmental and endurance test methods for solder joints»).
5

1.0—2012 ().
1) « » , « » ()
» .
« » ,
—
(gosi.ru).

1	1
2	1
3	2
4	3
5	5
5.1	5
5.2	,	7
5.2.1	7
5.2.2	,	9
6	10
6.1	10
6.2	11
6.2.1	11
6.2.2	11
6.2.3	12
6.3	14
6.3.1	(.....	14
6.3.2	(.....	14
6.3.3	(.....	14
	Sn89Zn8Bi3).....	14
6.4	14
7	15
7.1	15
7.1.1	15
7.1.2	15
7.1.3	16
7.1.4	16
7.1.5	17
7.2	17
7.3	19
7.4	20
7.4.1	20
7.4.2	21
7.5	,	21
7.5.1	,	21
7.5.2	,	22
()	23
()	25
()	26
D()	29
()	31
F()	33
G()	34
()	36
(,	38
)	39

55492—201 /PAS 62137-3:2008

(IEC) 62137-3

91: «

».
IEC/PAS 62137-3,

2008 ,

IEC 62137

web-

«

».

55492—2013/IEC/PAS 62137-3:2008

3

Electronics assembly technology. Part 3. Selection guidance of environmental and endurance test methods
for solder joints

— 2013—12—01

1

1*

(SMD).

2

().

60134

(*Printed board design, manufacture and assembly— Terms and definitions*)

61188-5 ()

(*Printed boards and printed board assemblies— Design and use*)

61249-2-7

2-7.

(),

[*Materials for printed boards and other interconnecting structures — Part 2-7: Reinforced base materials clad and unclad — Epoxide woven E-glass laminated sheet of defined flammability (vertical burning test), copper-clad*

62137-1-1:2007

1-1.

(*Surface mounting technology — Environmental and endurance test methods for surface mount solder joint—Part 1-1: Pull strength test*)

62137-1-2:2007

1-2.

(*Surface mounting technology — Environmental and endurance test methods for surface mount solder joint—Part 1-2: Shear strength test*)

oe

55492—201 /PAS 62137-3:2008

62137-1-3:2008

1-3.

(*Surface mounting technology — Environmental and endurance test methods for surface mount solder joint — Part 1-3: Cyclic drop test*)

62137-1 -4:2009

1-4.

(*Surface mounting technology — Environmental and endurance test methods for surface mount solder joint — Part 1-4: Cyclic bending test*)

62137-1-5:2009

1-5.

(*Surface mounting technology — Environmental and endurance test methods for surface mount solder joints — Part 1-5: Mechanical shear fatigue test*)

3

60194.

3.1 (pull strength for SMO):

« »

45*

[IEC 62137-1-1:2007.

]

3.2 (shear strength for SMD):

[IEC 62137-1-1:2007,

]

3.3

(torque shear strength for SMO):

3.4

(monotonic bending strength for SMO):

3.5
bending strength for SMO):

(cyclic

[IEC 62137-1-4:2009,

]

3.6

(mechanical shear fatigue strength for SMO):

(

),

3.7 (cydic
drop test for SMD):

3.8 (cydic steel ball
drop strength for SMD):

3.9 (pull
strength for lead insertion type device):

3.10 (creep strength for lead insertion type device):

3.11 (fillet lifting phenomenon for lead insertion type device):

().
3.12 (daisy chain):
(. .2).

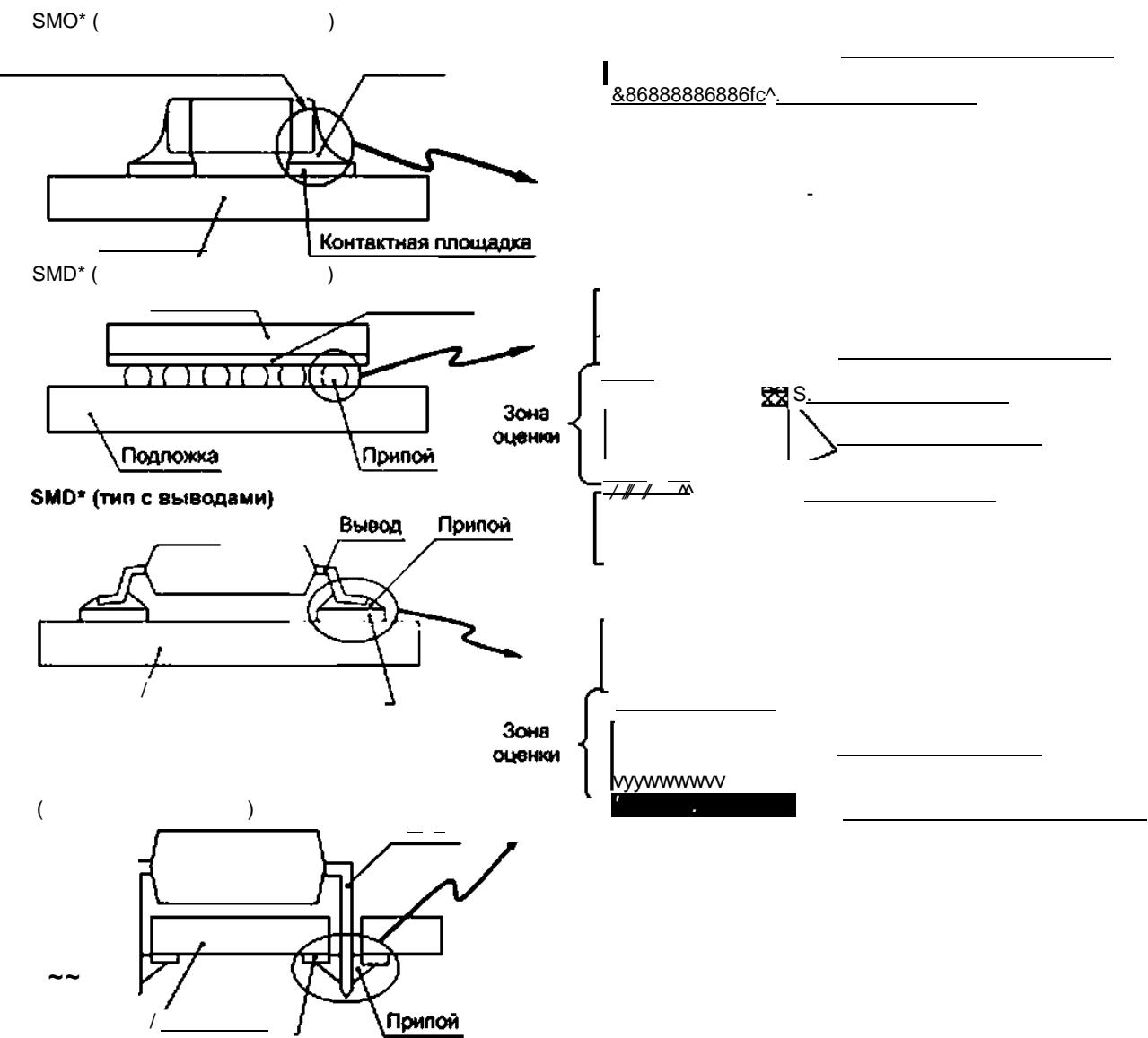
4

1.

Sn96.5Ag3Cu.5.

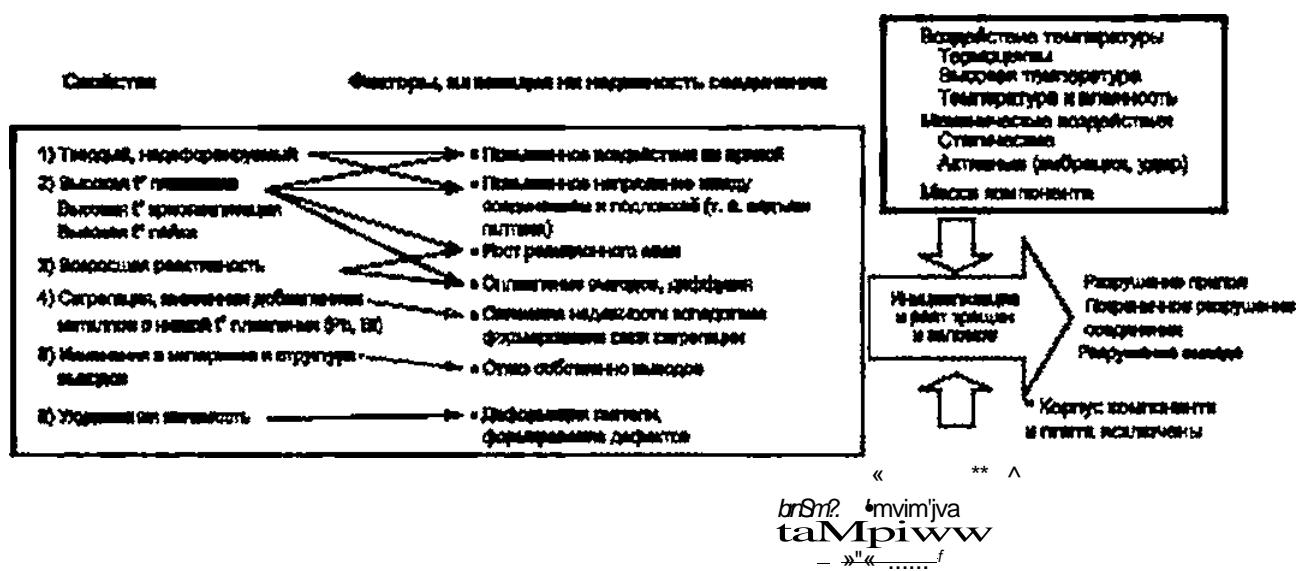
2.

55492—201 /PAS 62137-3:2008



1 —

SMD —



2 —

5

5.1

1.

5.2.

1 —

{)		/ .	,
8 ** *	*1	(SMO)	a)
62137-1-1 **	*1 **	{SMD}. »	b)
62137-1-2 *1		(SMO)	c)
**		(SMD)	
		(SMD)	

55492—201 /PAS 62137-3:2008

1

()		/ ,	,
- 41 62137-1-4		- (SMD)	- ,
- 62137-1-5		- (SMD)	- /
- ** 62137-1-3		- (SMD)	- ,
- ** F	0	- ,	- /
- G		- ,	
-	4*	- ,	- /

>

BGA LGA.

)

1)
2)
3):Sn-Zn.
Sn-8i.

Sn-2n. Sn-Bi Sn-In.

Sn-Zn. Sn-Bi Sn-In.

>

5.2

5.2.1

2.

2 —

							S	3 3 1 S _s II ₃ 3	%	0 1 S X 2 3	X X X 9 6 X 3	X § 9 6 X 2 >>	
z * S § 2 0 1 » 2 5 ?	() -		2	.	-	.	.8						
	-		2	-	.	-	.8						
	-		2	.	,	,	.8						
	() -		4	.	-	.	.8						
	« » — 1		4	.		.	.						
	« » — 2		6	.		.	.						
	« » —		4	.		.	.8	.8
			2	.	-	-	.8	
	,		2	MELF /	/	-	—	.8	—	—	—	—	—

														339 ? 25 \$ 9 >
					• 9 5 5 s	1 1 & 9 ;				≤0 £ 5 s	0 S «X 1 ? X 3			
				2	0 »	2 3	o							
	()	-		2		—	.8			—	—	—	—	
2	« »			3 6			8			—	—	—	—	
0	• »	/ 	6		QFP. SOP	.							8	8
« 2	/ Sr													
8			6		OFN. SON				,		8	8	8	
1456S.		(1)	-		BGA.FBGA				.		8	8	8	
		l	-		LGA. FLGA				.		8	8	8	

1 « » —

«» —

« » —

2

a)
b)

c)

3

BGA. LGA QFN.

2

6

}
b>
)
7

:
Sn-Zn;
Sn-Bi.

Sn-Ag-Cu. Sn-Zn. Sn-Bi SrHn;

60191.

« BGA »

5.2.2

3.

3 —

			—	—	—
			—	—	—
			—	—	—
		—	—		

1 « » —

2)
>

c)
d)

3

4

5

Sn-Ag-Cu Sn-Zn.

55492—201 /PAS 62137-3:2008

6.1
)

4.

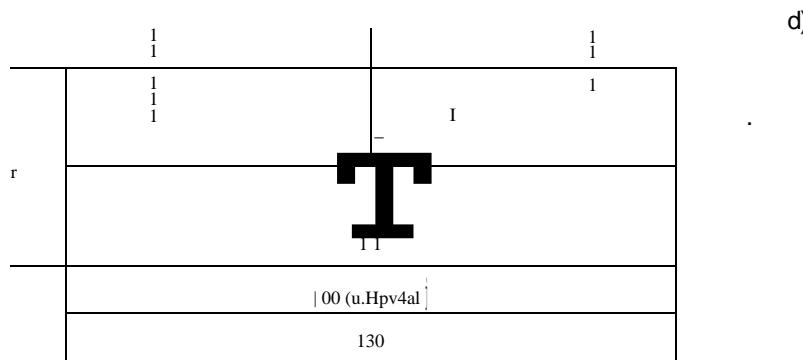
4 —

	()	
Sn-Ag-Cu	Sn96.5Ag3Cu.5(A30C5>	—
Sn-2n	Sn912n9<290)	Sn892n8B 13(280830)
Sn-Bi	Bi56Sn42(B580)	—
Sn-In	Sn88In8Ag3.5Bi.5(N80A3585)	—
Sn-Cu	Sn99.3Cu.7(C7)	—

b)

61249-2-7

c)



3—

61168-5.

5 —

(S). ²	ftf) ,	,	,
S s 0.10	d > 0.35		1.4
0.10 < S & 0.28	0.35 < d < 0.60	1.0	1.8
0.28 < S S 0.50	0.60 < d < 0.80	1.2	1.8
0.50 < S < 0.79	0.80 < d < 1.00	1.4	2.0
0.79 < S s 1.20	1.00 < d < 1.25	1.6	2.2

6.2

6.2.1

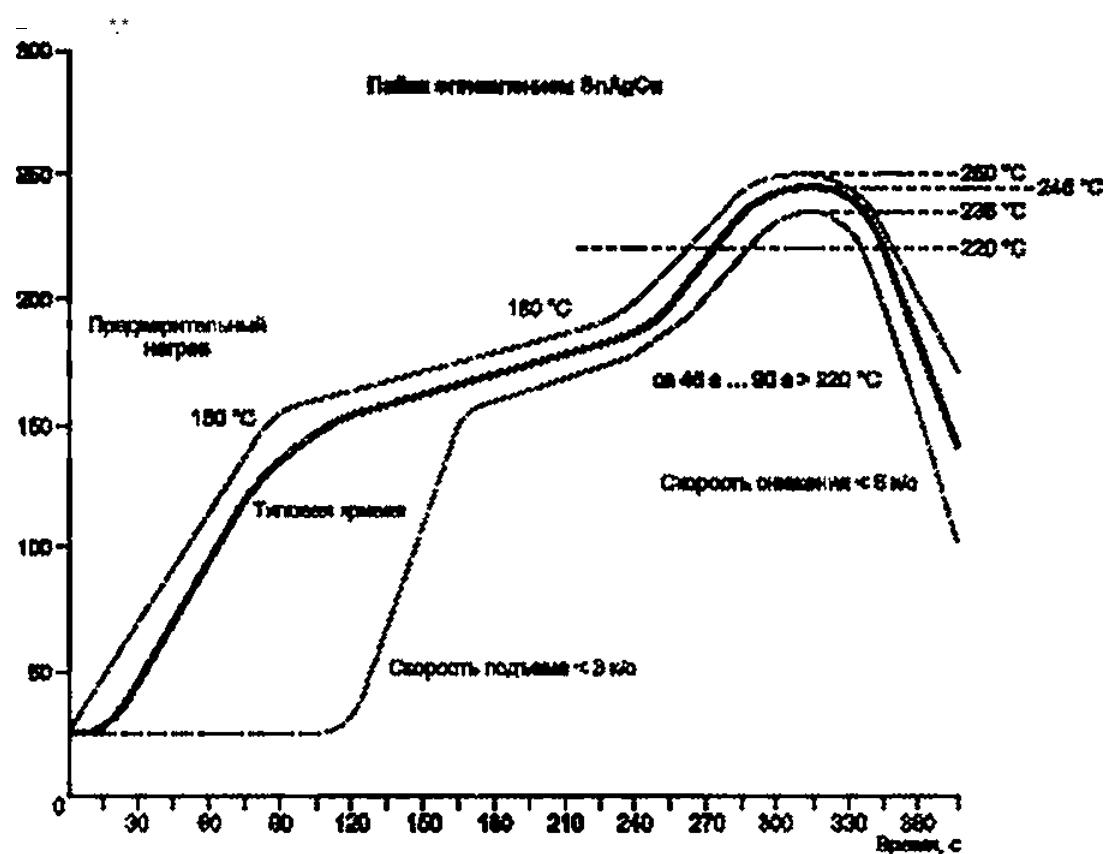
6.2.2

6.2.3

6.2.2

Sn96,5Ag3Cu.5

4.

61760-1.
5.

),

(

).

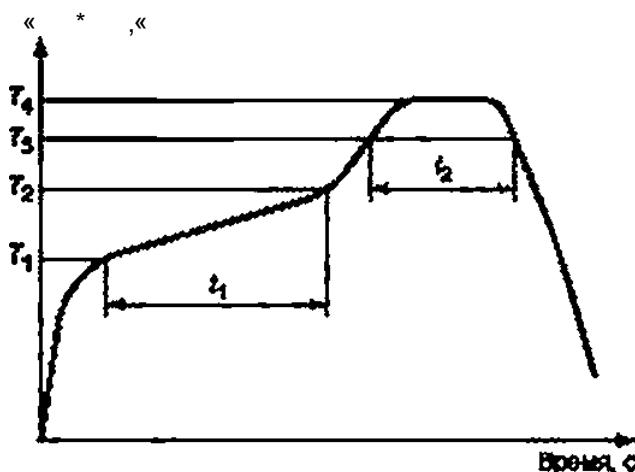
(

},

4 —

(Sn96,5Ag3Cu.S)

55492—201 /PAS 62137-3:2008



		Bn9tZn»*. Sn89Zn8B»3	BiSeSn42	Sn88tn8Ag3.SBi.S
h		130 X	100 X	140 '
2		1S0X	120 X	160 X
h		200 X	150 '	206 X
*		220 *Cl5*C	190 X ± 5 X	220 X X 5 X
		90 30	90 130	90 130
>2		20 60	20 60	20 60
N_2 .				

5 —

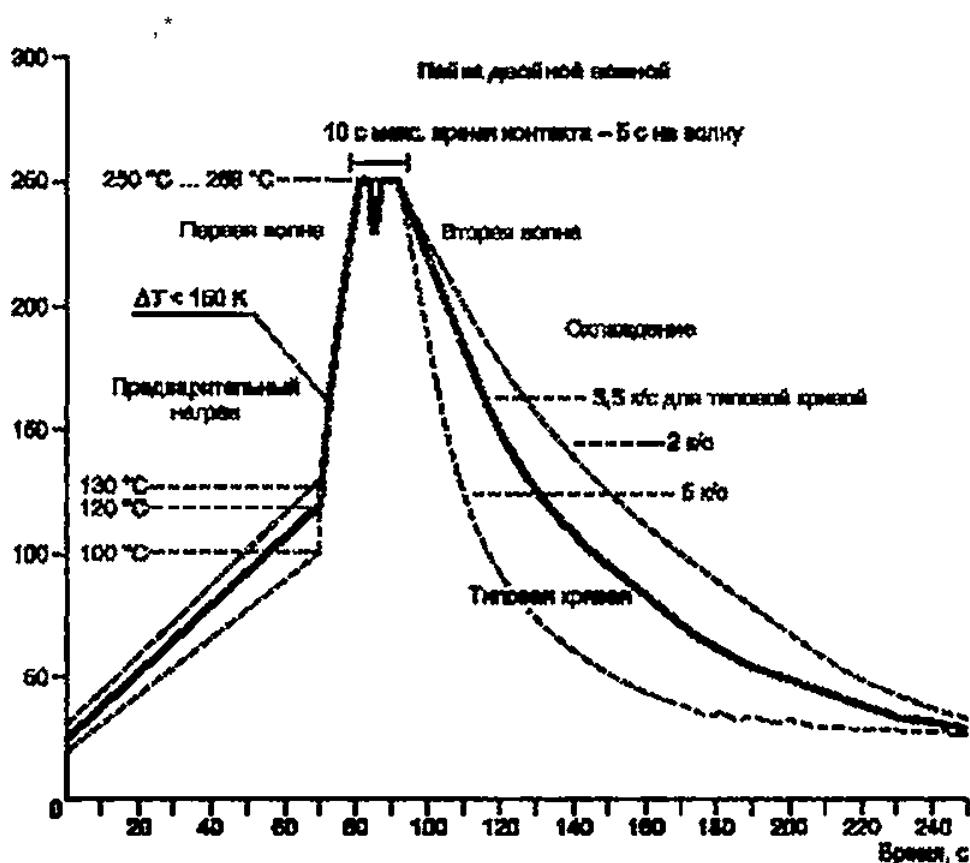
, Sn96.5Ag3Cu.5

6.2.3

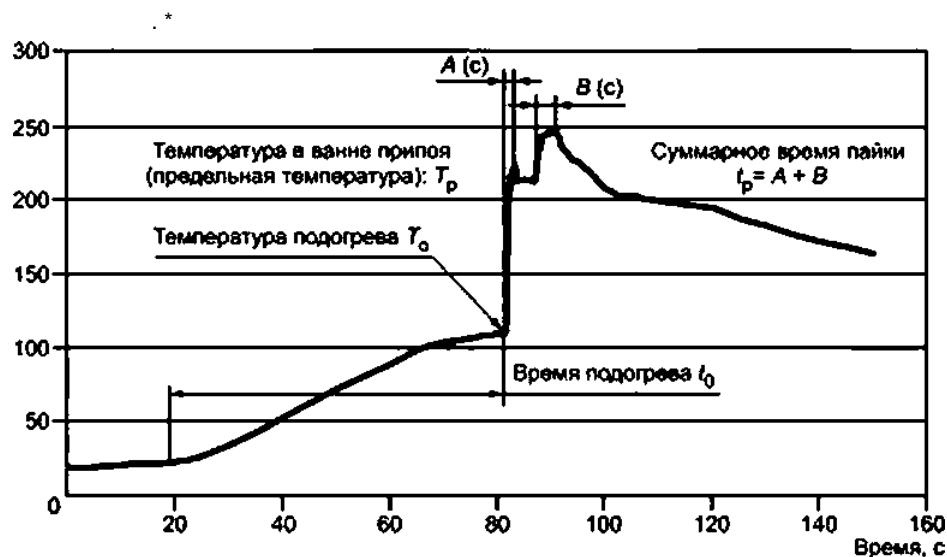
Sn96.5Ag3Cu.5

6

7.



6 — ().
 : ().
 : ().
 {
),
 : ().
 6 — ().
 (Sn96.5Ag3Cu.5)



	T_o				#	
Sn99.3Cu.7(C7)	100 *	120 *	30	90	250 *	25 *
					3	5

55492—201 /PAS 62137-3:2008

6.3

6.3.1

)

N (60068-2-14.

(

),

,

,

,

(

),

(

).

6.

500 1000.

6 —

		Sn96. SAgDCu.S	Sn912n9. Sn89Zn8Bi3	BiS8Sn42	Sn881n8Ag3.SBi.5
-	-	-40 *	-40 *	-40 *	-40 *
	-	30	30	30	30
-	-	125 *	125 *	85 *	125 '
	-	30	30	30	30

6.3.2

()

Bi58Sn42)

60066-2-2,

,

,

,

,

,

,

,

,

,

,

,

,

,

,

,

,

,

,

,

,

,

,

,

,

,

,

,

,

,

a) : 85 *

b) : 500 1000 .

6.3.3

Sn91Zn9 Sn89Zn8Bi3)

()

()

60066-2-78,

,

a) : 65 ® . 85 %.

b) : 500 1000 .

6.4

)

/

b)

c)

7

7.1

7.1.1

7.1.2

«

».

8.

45°.

0.5

0.0083 / (0,5 /).

(QFP)

62137-1-1.

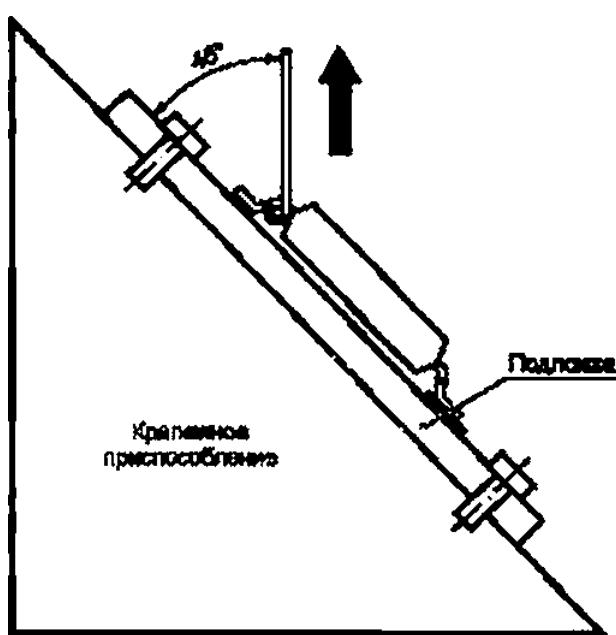
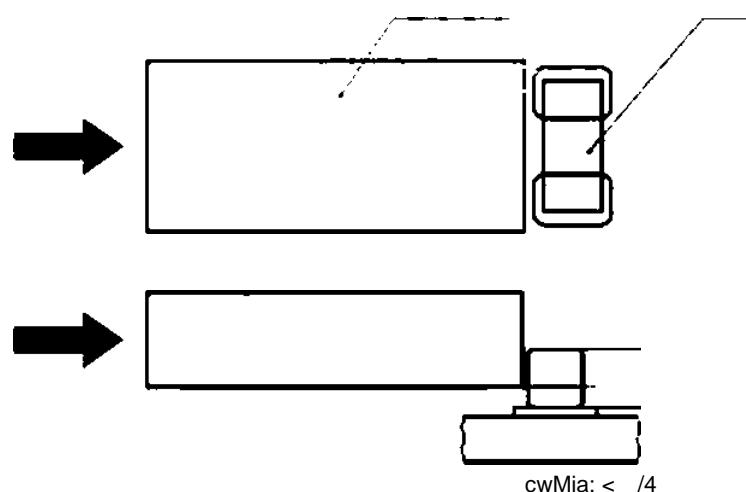


Рисунок 8 — Испытание прочности на отрыв

55492—201 /PAS 62137-3:2008

7.1.3

9.



9 —

*/4

0.0083 / 0,15 / (0,5 / 9 /).

62137-1-2.

7.1.4

10.

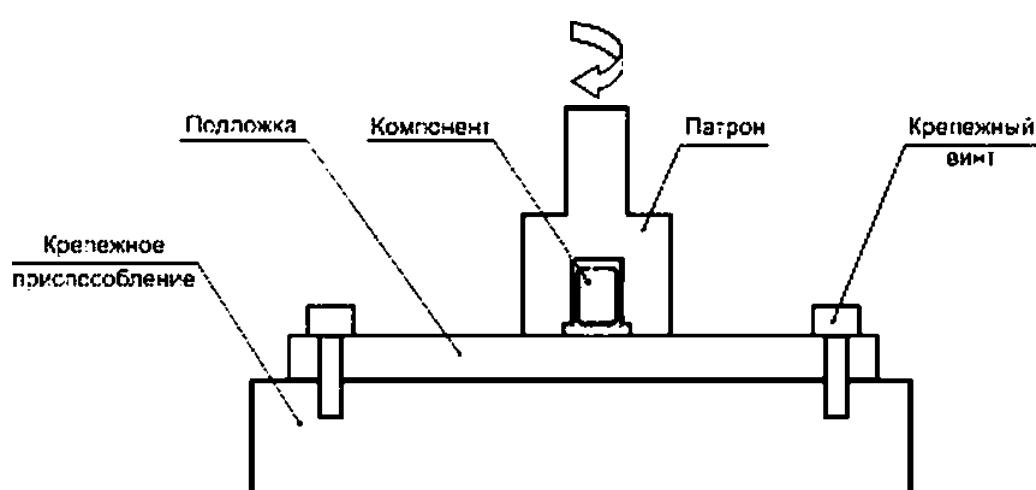
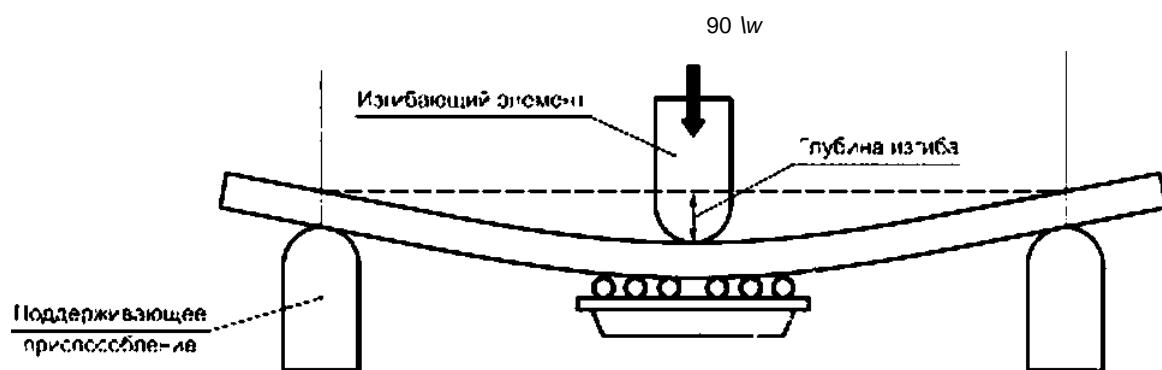


Рисунок 10 — Испытание на прочность при приложении крутящего момента

0.00698 / 0,017 / .

7.1.5

11.



11 —

(D.2.3).

5

90

R 2.5

1.6 0.0083 / (0.5 /).

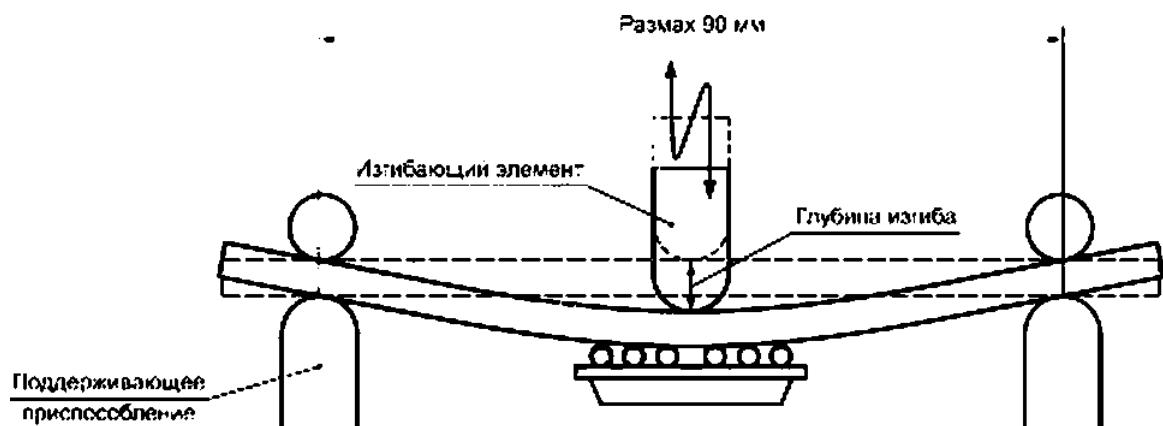
— 10

D.

7.2

12.

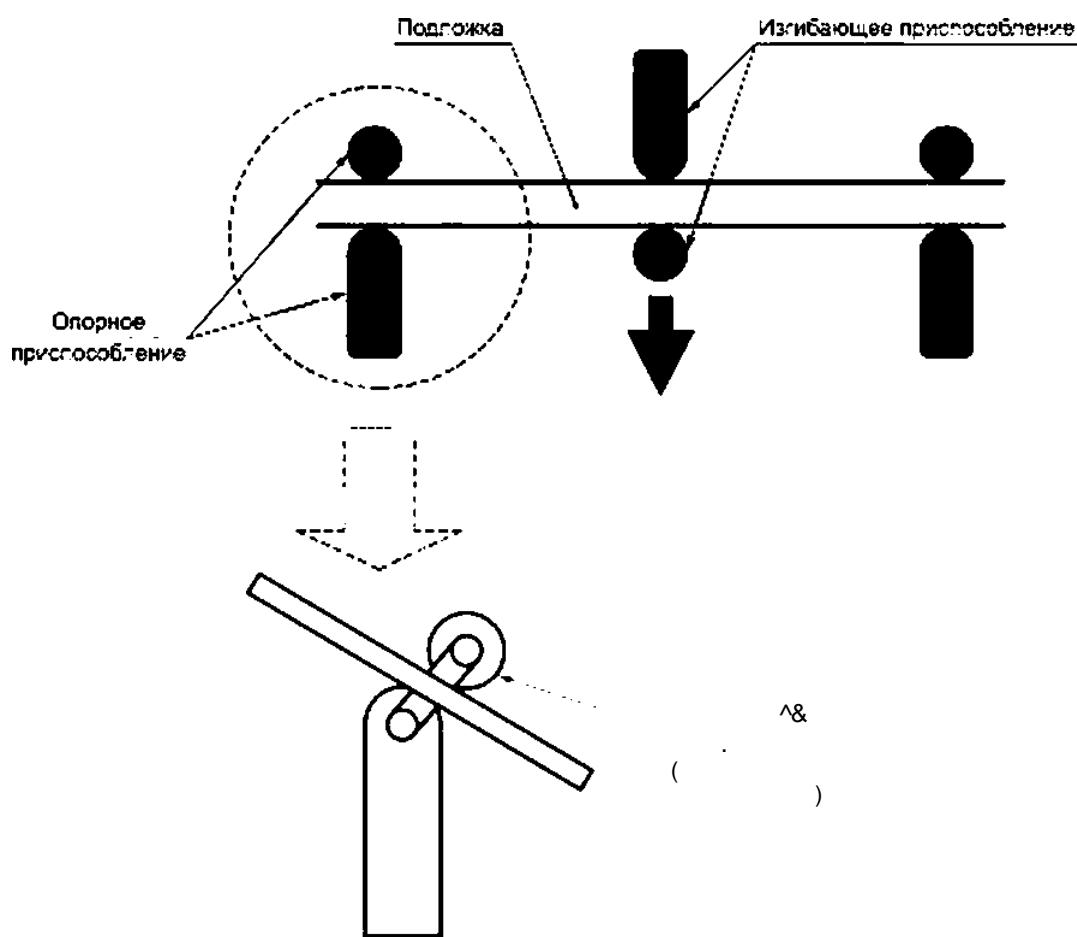
55492—201 /PAS 62137-3:2008



12—

(. . 0.2.4).

13



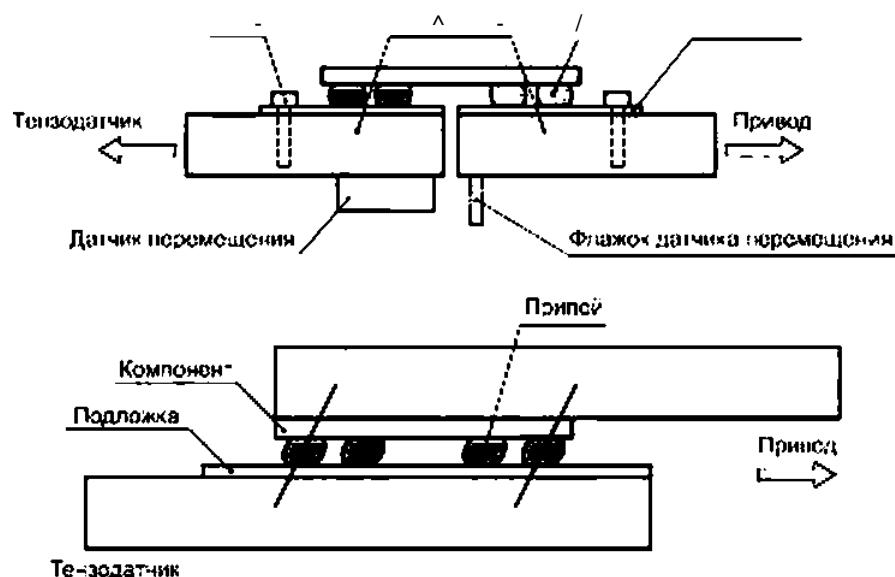
13 —

0.5 / (30 /).

62137-1-4.

7.3

14.



14 —

25

55492—201 /PAS 62137-3:2008

6,

(. D.2.4).

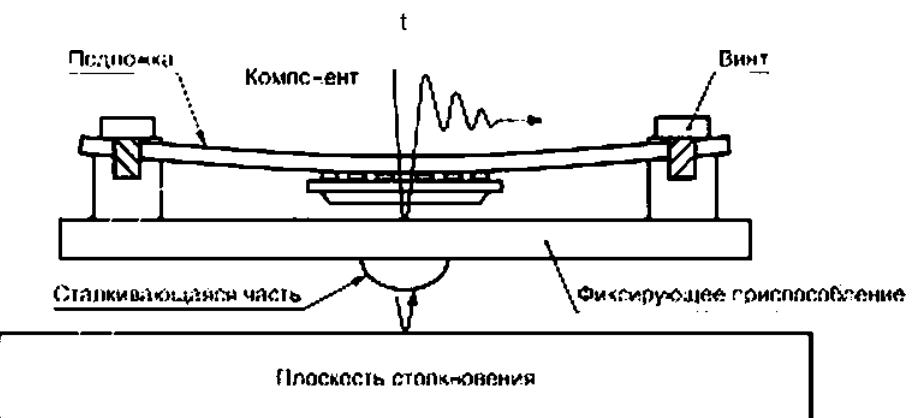
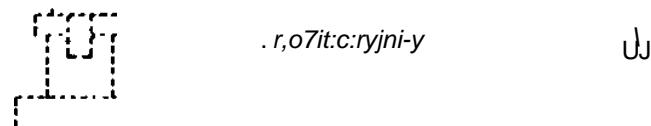
62137-1-5.

7.4

7.4.1

15,

(. D.2.4).



15 —

0.8 1.2
1.6

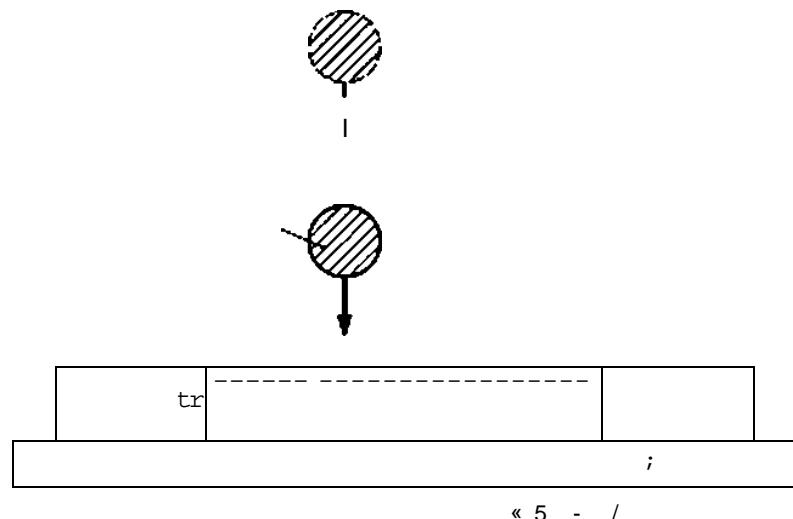
62137-1-3.

55492—2013/IEC/PAS 62137-3:2008

7.4.2

16,

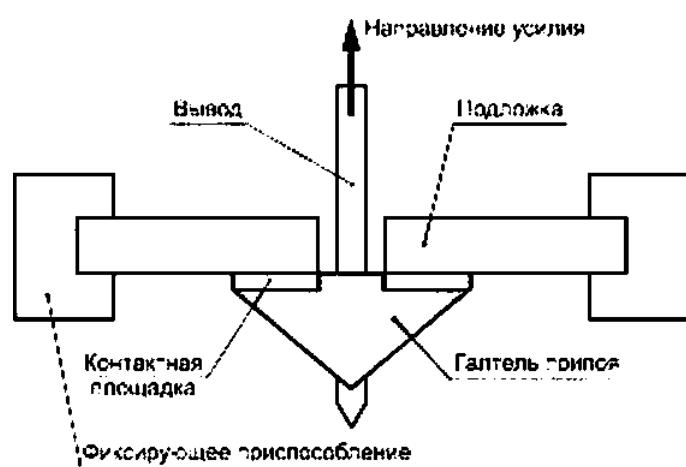
(. D.2.4).



7.5

7.5.1

17.



17 —

55492—201 /PAS 62137-3:2008

20 / . 1 / , 2 / , 5 / , 10 /
F.

7.5.2

18.

{ . D.2.4).

0.4

0.6

50

125 *

(7).

G.

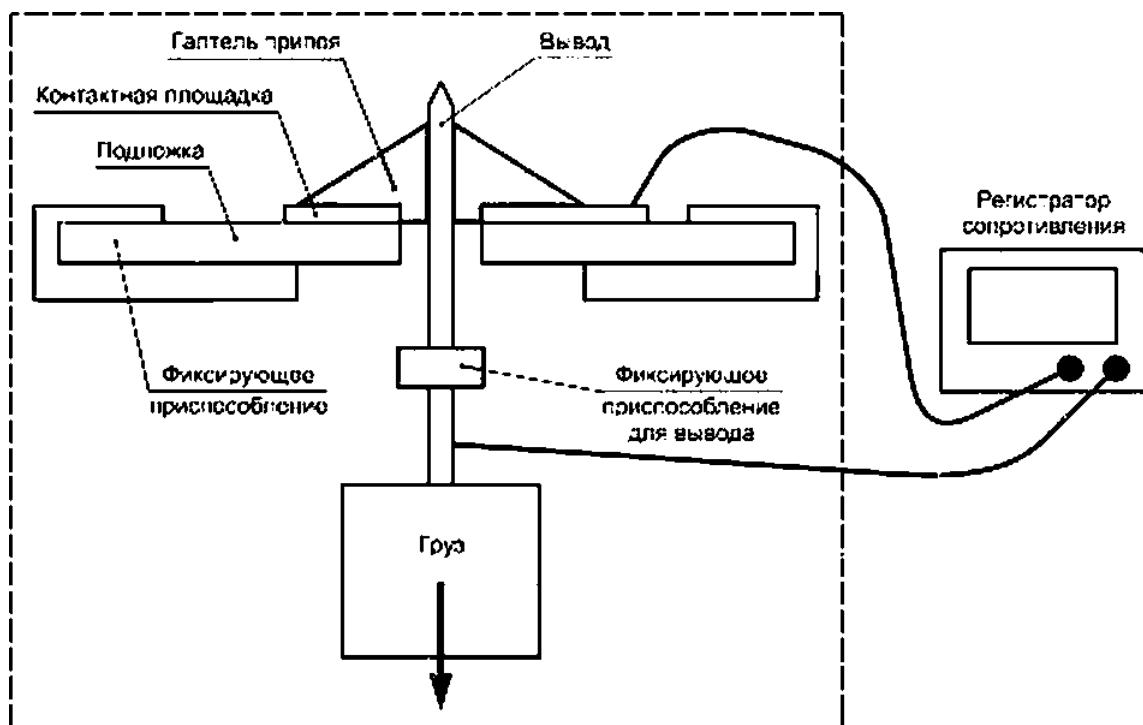


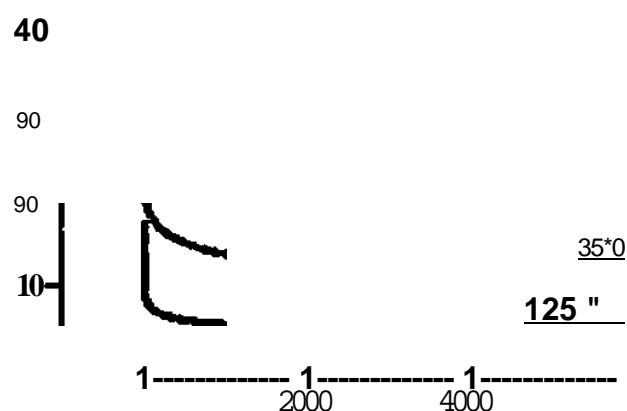
Рисунок 18 — Испытание на сопротивление ползучести

()

.1

6.3.1.

.2

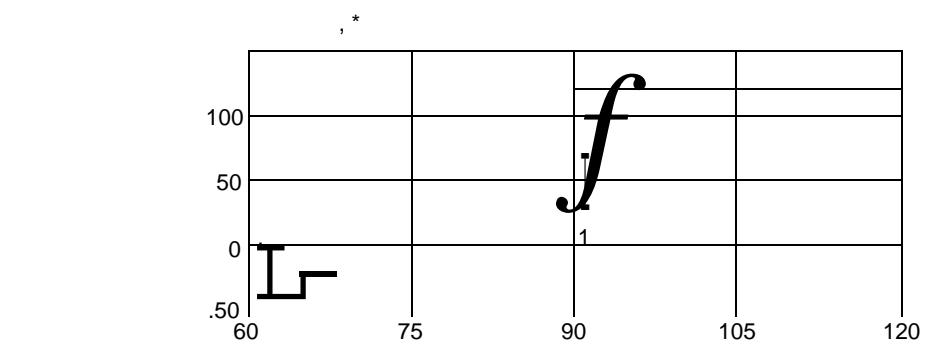


(Sn96.SAg3Cu,5)

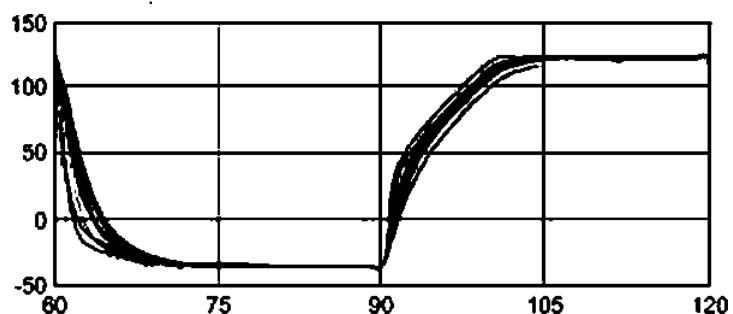
15

15

55492—201 /PAS 62137-3:2008



) (0) ,



) (240) ,

.2 — ,

.4

(15) .

' / () 30 , ,

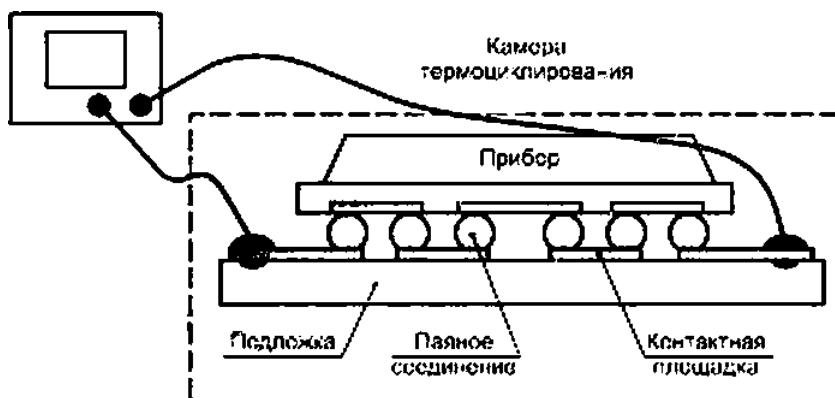
()

.1

BGA, LGA.

.2

.1.



1 —

.6.1.

6.4

62137.

55492—201 /PAS 62137-3:2008

()

.1

7.1.4.

.2

.2.1

.2.3.

.2
.2.2

.1.

.2.3
.2.3.1

.2.3.2

0.00698 / 0.015 / .

.2.3.3

(. . .).

.2.3.4

0.00698 / 0.015 / .

.2.4

.2.4.1

.2.4.2

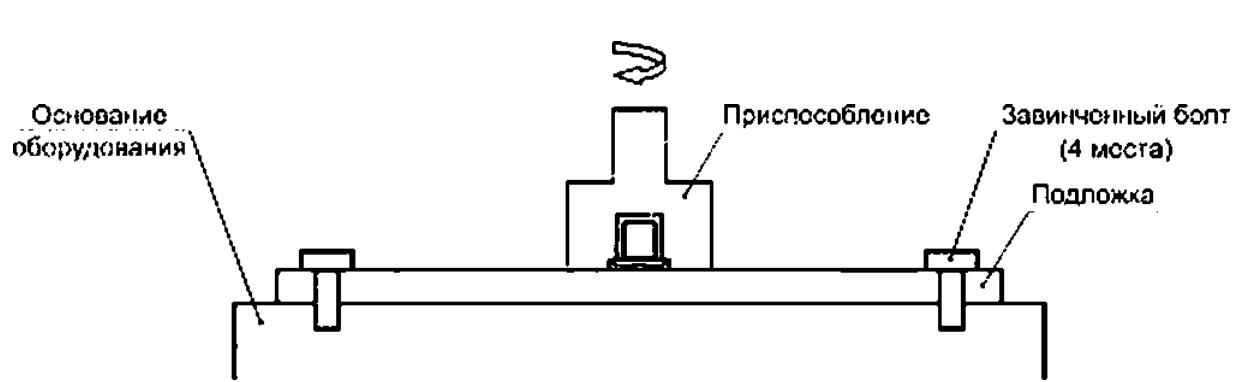
.2.4.3

0.00698 / 0.015 / ().

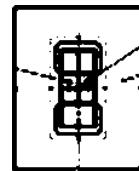
.2.4.4

.2.4.5

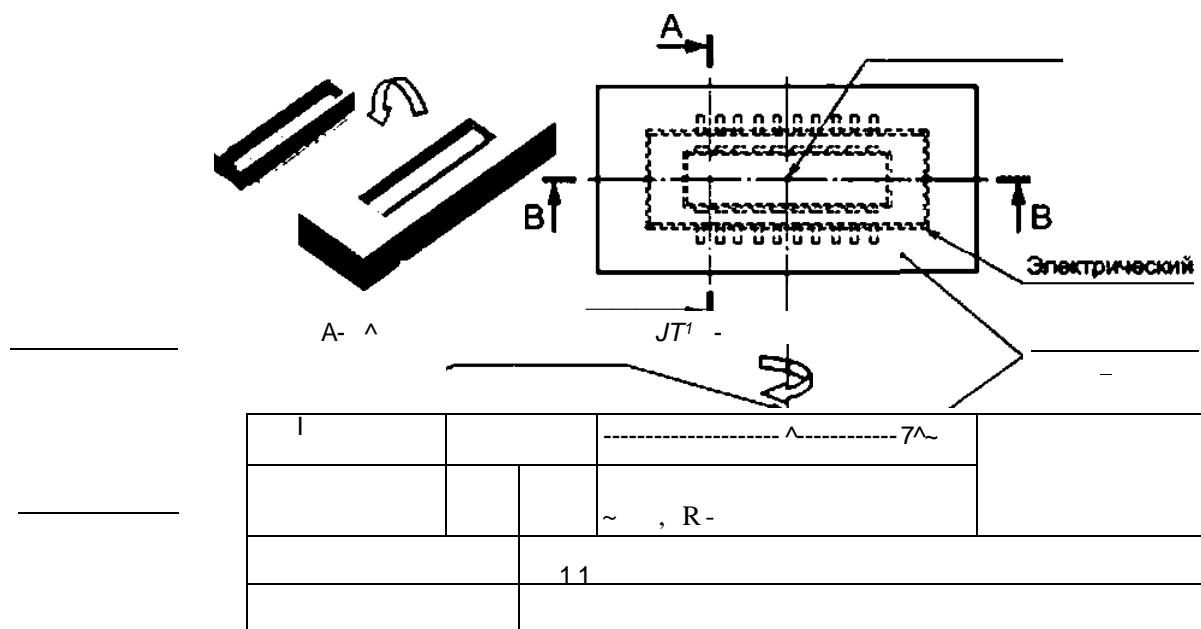
0.00696 / 0.015 / .



55492—201 /PAS 62137-3:2008



.2 —



()

0.1

7.1.5.

D.2

0.2.1

:

0.2.2

7.1.5.

a)

(20).

*1 %

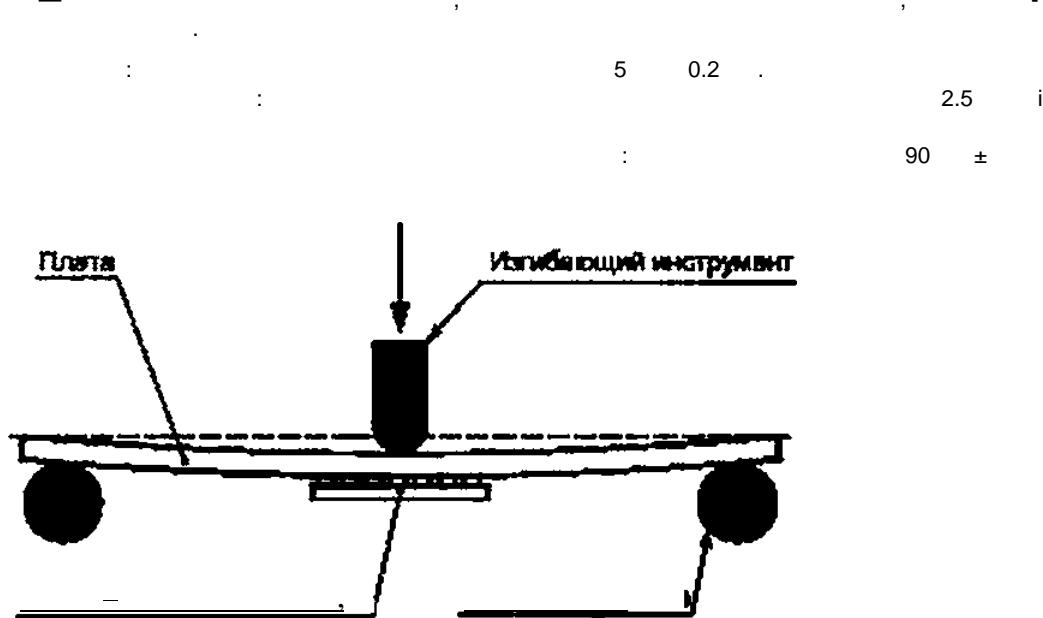
b)

0.2.3

().

0.1

a)



D.1 —

0.2.4

1 10 .
 10 100

55492—201 /PAS 62137-3:2008

0.2.5

0.3

)

•

•

•

(4S ± 0.5);

•

•

0)

)

10

0)

0.4

0,0083 / 0.1 / (0.5 / 6 /).

()

.1

7.4.2.

BGA.LGA OFN.

().

.2

6.1.

1.6

7.4.2.

.4

.1.

(. 0.2.4).

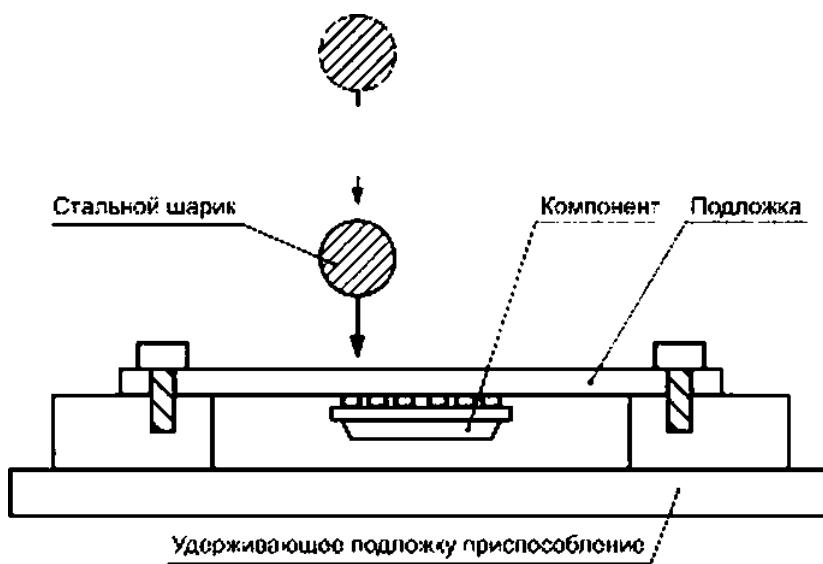


Рисунок Е.1 — Циклическое испытание на падение

55492—201 /PAS 62137-3:2008

£.5

()

QFN 64

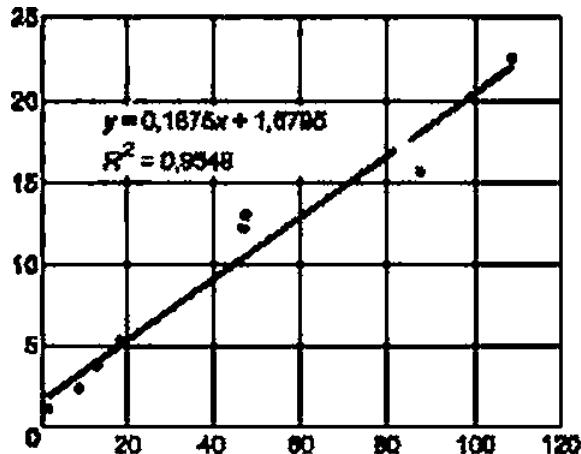
FR-4.

1.6

.2.

 \tan^* >

*



»

— 0.75

— 10

— 1.5

.2 —

() F

F.1

7.5.1.

F.2

5.3 a) 60068-1.

4

b)

F.1.

c)

1

2

3

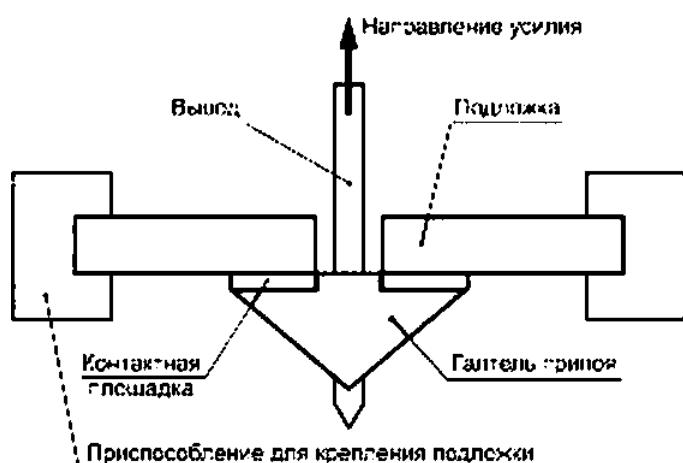
d)

: 0.0167 / (1.0 /), 0.033 / (2.0 /). 0.063 / (5.0 /), 0.167 / (10 /).
 / (20 /).

e)

)

)



F.1 —

55492—201 /PAS 62137-3:2008

()

G.1

7.S.2.

G.2

) b)

10

c)

1 —

)

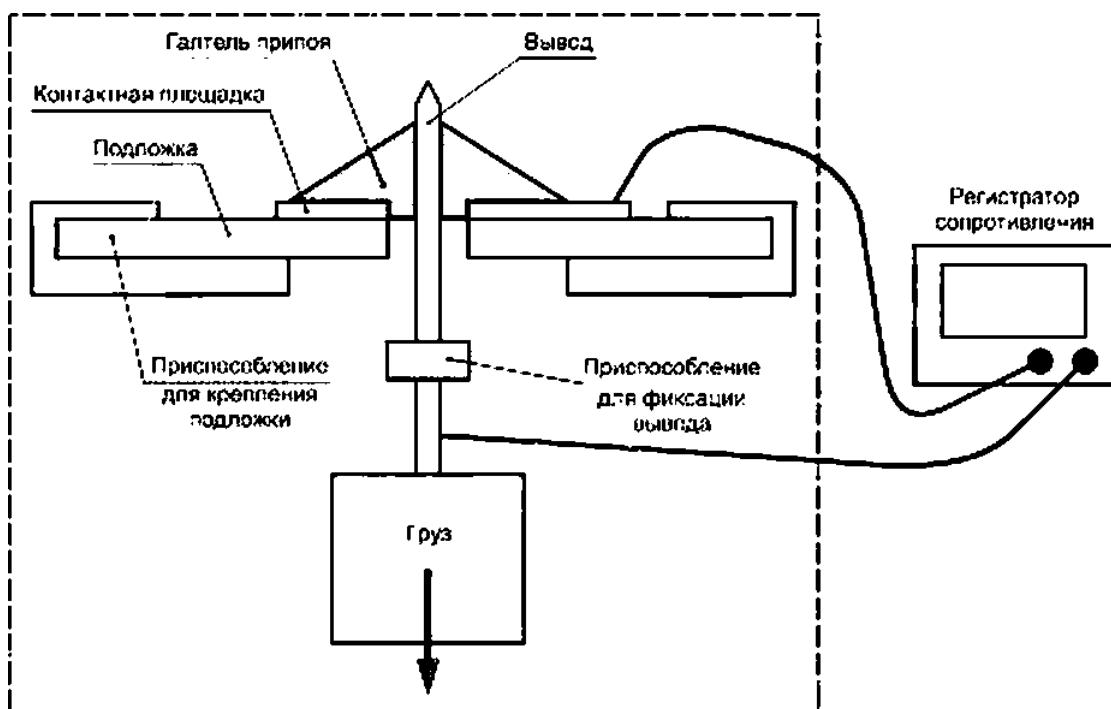
2 —

3 —

4 —

)

G.1.



G.1 —

55492—2013/IEC/PAS 62137-3:2008

)

,
t1 %.

5 —

,

6 —

7 —

(. . 90 %

()

).
,

)
h)

l)

8 —

,

,

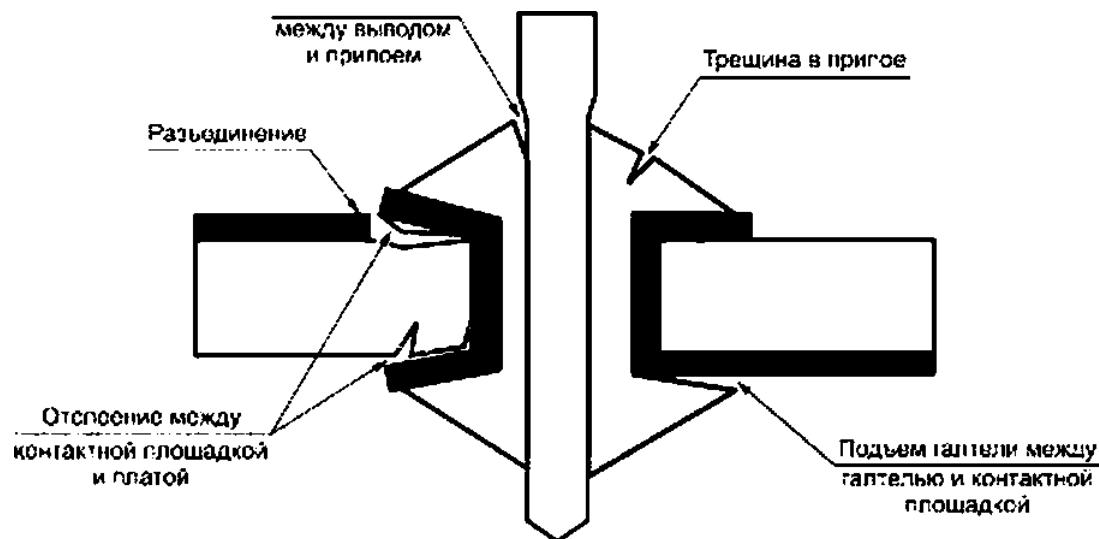
55492—201 /PAS 62137-3:2008

()

.1

.1.

-
-
-



.1 —

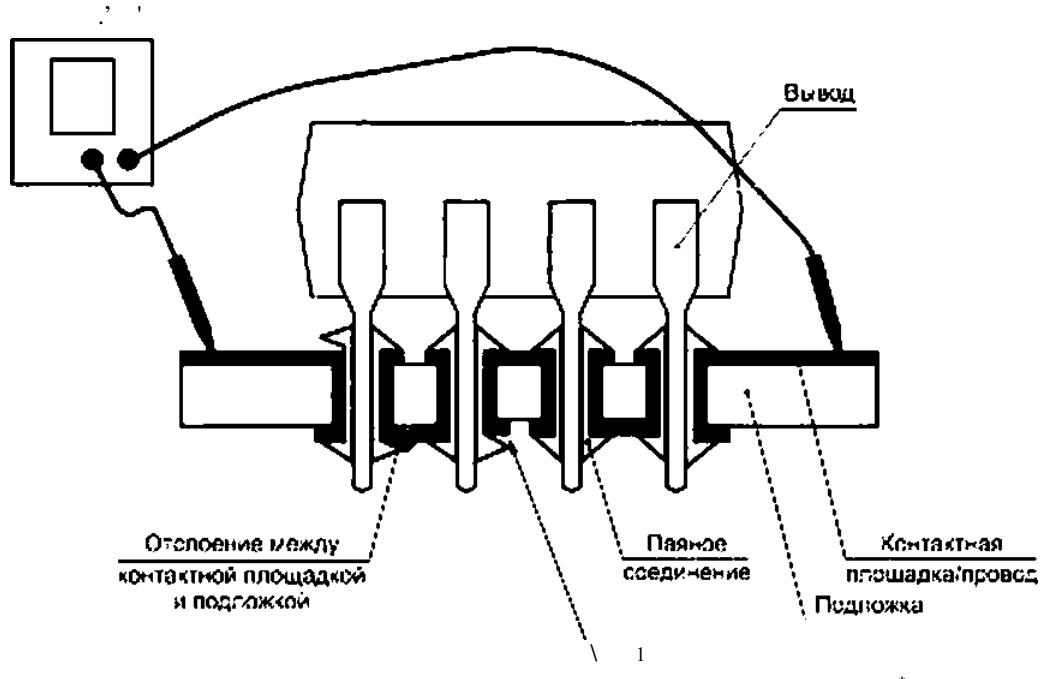
.2

10° — 30°

6.3.

.2.

{ . 0.2.4).



.2 —

55492—201 /PAS 62137-3:2008

()

.1

6 >		
60068-1:1908		28198—89 (68-1—88) « » 1.
60068-2-2		60068-2-2—2009 « 2-2. »
60068-2-14		28209-89 (66-2-14—84) « » 2. N:
60068-2-78		60068-2-76—2009 « 2-78. Cab: , »
60194	NEO	53386—2009 « »
61188-5	—	
61249-2-7		26246.7—89 (249-2-7—87} « (). »
61760-1	—	
62137-1-1:2007	NEO	20.57.406—81 « »
62137-1-2:2007	NEO	20.57.406—81 « »
62137-1-3:2008	NEO	20.57.406—81 « »
62137-1-4:2009	NEO	20.57.406—81 « »
62137-1-8:2009	NEO	20.57.406—81 « »
* — • — - MOD — • NEQ —		

55492—2013/IEC/PAS 62137-3:2008

IEC 60068-1:1998
 (Environmental testing—Part 1: General and guidance)
 IEC 60068-2-2
 (Environmental testing—Part 2-2: Tests—Test 2: Dry heat)
 IEC 60068-2-14
 (Environmental testing—Part 2-14: Tests—Test N: Change of temperature)
 IEC 60068-2-78
 (Environmental testing—Part 2-78: Tests—Test Cab.
 Cab: Damp heat, steady state)
 IEC 61760-1
 (Surface mounting technology—Part 1: Standard method (or the specification of surface mounting components fSMDs))
 IEC 62137:2004
 FBGA. BGA.
 FLGA. LGA. SON OFN (Environmental and endurance testing—Test methods for surface-mount boards of area array type packages FBGA. BGA. FLGA. LGA. SON and OFN)

621.396:69:006.354

OKC 31.190

02

(SMD);

8.

OJJ-

09.04.2014.	22.05.2014.	60 > 84 [▲]
.
4.05.	4.80.	60 . . . 2120.
« 4.
www.gosbnfo.ru		mfo@gosbnfo.ru